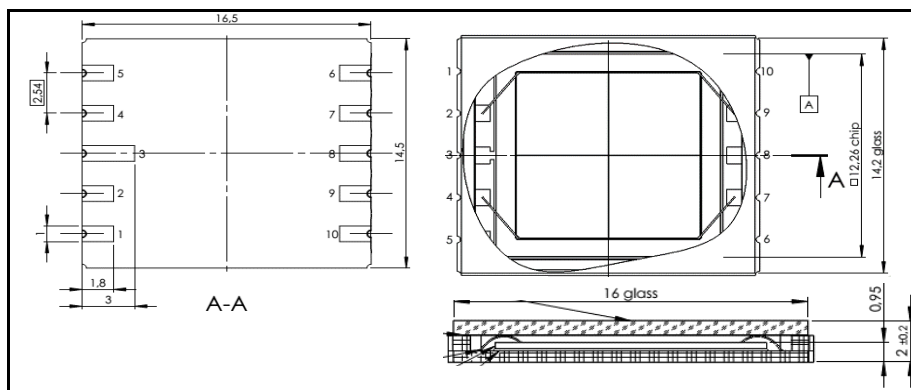
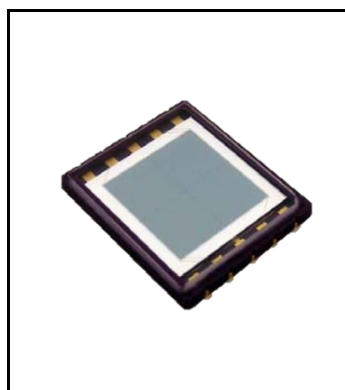




Features

- Quadrant detector
- Low dark current
- Fast rise time, low capacitance
- High QE at 1064 nm

Description

Square active area quadrant PIN detector with 4 x 25 mm² and 50 µm gaps, optimized for 1064 nm. Quasi-hermetic ceramic carrier type package with glass cover (reflow solderable).

Application

- 1064 nm laser detection
- High speed photometry
- NIR pulsed light sensor
- Laser guidance

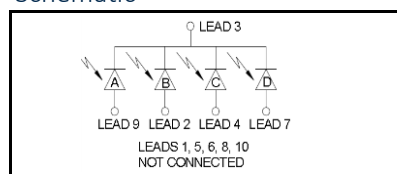
RoHS

2011/65/EU

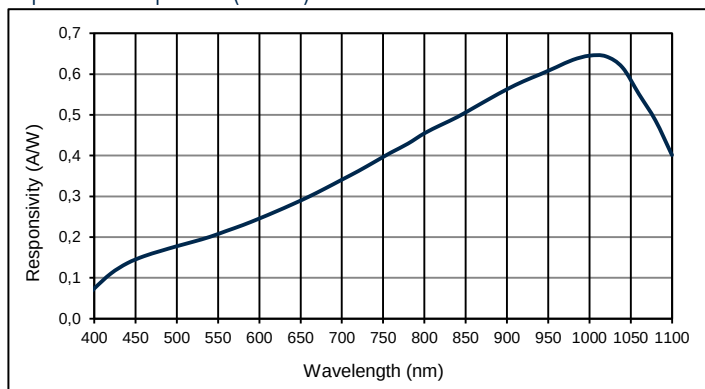
Absolute maximum ratings

Symbol	Parameter	Min	Max	Unit
T _{STG}	Storage temp	-55	125	°C
T _{OP}	Operating temp	-40	85	°C
V _{OP}	Operating voltage		250	V
I _{PEAK}	Peak DC current		10	mA

Schematic



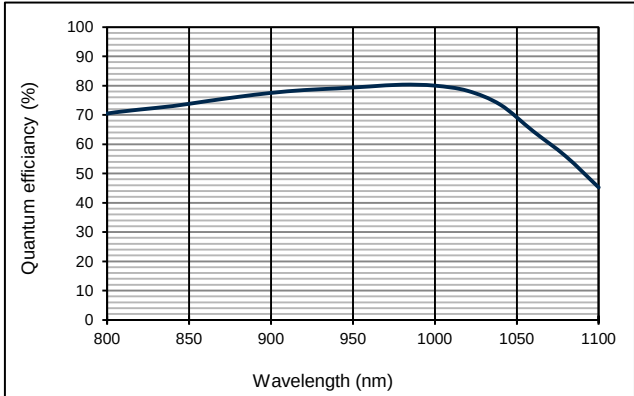
Spectral response (23 °C)



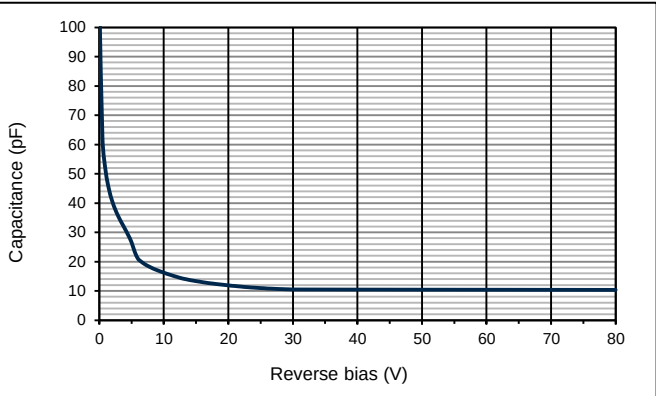
Electro-optical characteristics @ 23 °C

Symbol	Characteristic	Test Condition	Min	Typ	Max	Unit
	Number of elements		4 quadrants			
	Active area		10 x 10			mm
	Active area	per element	25			mm ²
	Gap	between elements	50			µm
I _D	Dark current	V _R = 150 V, per element		6.5	20	nA
C	Capacitance	V _R = 150 V, per element		10		pF
	Responsivity	V _R = 150 V; λ = 1064 nm; R _L = 50 Ω	0.42	0.48	0.65	A/W
t _R	Rise time	V _R = 180 V; λ = 1064 nm; R _L = 50 Ω		12		ns
V _{BR}	Breakdown voltage	I _R = 2 µA	250			V
	Temperature coefficient	Change of I _{PH} with temperature		1.07		%/K
	Cross talk	V _R = 150 V; λ = 1064 nm; R _L = 50 Ω		2		%

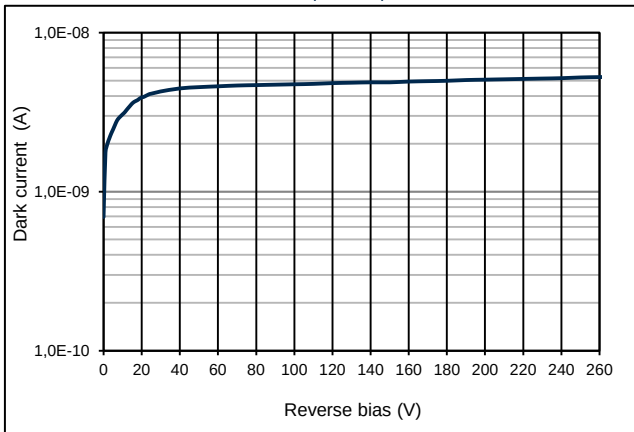
Quantum efficiency (23 °C)



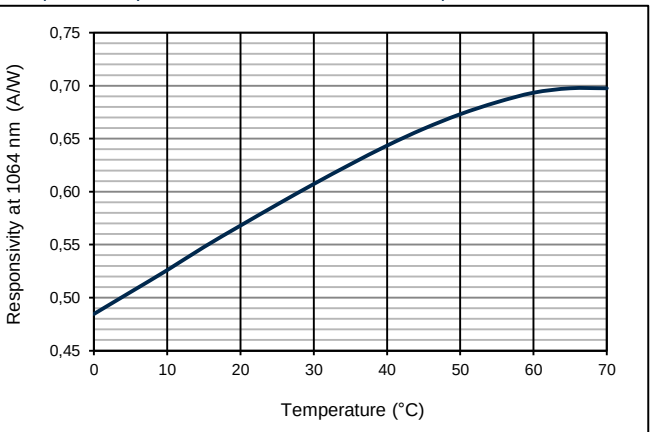
Capacitance as fct of reverse bias (23 °C)



Dark current as fct of bias (23 °C)



Responsivity at 1064 nm as fct of temperature



Package dimension:

Small quantities: Foam pad, boxed (12 cm x 16.5 cm)

Disclaimer: Due to our strive for continuous improvement, specifications are subject to change within our PCN policy according to JESD46C.